

Notic o f Ref rence s Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/705,174 MITCHELL ET AL.	
		Examiner	Art Unit	Page 1 of 1 Yoon-Young Kim 1723

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,827,854 B2	12-2004	Mitchell et al.	210/263
*	B	US-6,565,749 B1	05-2003	Hou et al.	210/500.38
*	C	US-6,660,166 B2	12-2003	Tremblay et al.	210/694
*	D	US-6,241,893 B1	06-2001	Levy, Ehud	210/660
*	E	US-5,772,896	06-1998	Denkewicz et al.	210/754
*	F	US-4,396,512	08-1983	Beauman et al.	210/668
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.